

BTA301-1000D

Rev.01 - 13 January 2025

3Q Triac

Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a TO92 plastic package. This "series D" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers and logic ICs including microcontrollers.

2. Features and benefits

- 3Q technology for improved noise immunity •
- Direct gate triggering from low power drivers and logic ICs
- High commutation capability with very sensitive gate
- High voltage capability
- Planar passivated for voltage ruggedness and reliability •
- Triggering in three quadrants only
- Very sensitive gate for easy logic level triggering

3. Applications

- Low power motor controls
- Small inductive loads e.g. solenoids, door locks, water valves .
 - Small loads in large white goods

4. Quick reference data

Table 1. Quick reference da

Symbol	Parameter	Conditions	Notes		Values	;	Unit
Absolute	e maximum rating						
V _{drm}	repetitive peak off-state voltage				1000		V
I _{T(RMS)}	RMS on-state current	square-wave pulse; T _{lead} ≤ 50 °C; <u>Fig. 1; Fig. 2</u> ; <u>Fig. 3</u>			1		A
I _{TSM} non-repetitive peak forward current		full sine wave; t_p = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5			11		А
		full sine wave; t_{p} = 16.7 ms; $T_{j(init)}$ = 25 °C			12.1		А
T _j	operating junction temperature			-40 to 125		25	°C
Static ch	aracteristics						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T2+ G+ T _j = 25 °C; <u>Fig. 7</u>		0.25	-	5	mA
		V _D = 12 V; I _T = 0.1 A; T2+ G- T _j = 25 °C; <u>Fig. 7</u>		0.25	-	5	mA
		V _D = 12 V; I _T = 0.1 A; T2- G- T _j = 25 °C; <u>Fig. 7</u>		0.25	-	5	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	10	mA
V _T	on-state voltage	I _τ = 0.85 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.30	1.60	V

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Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Dynamic characteristics							
dV _D /dt	rate of rise of off-state voltage	$V_{DM} = 670 \text{ V}; \text{ T}_{\text{j}} = 125 \text{ °C}; (V_{DM} = 67\% \text{ of } V_{DRM}); exponential waveform; gate open circuit$		-	150	-	V/µs
dl _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V}; \text{ T}_j = 125 \text{ °C}; \text{ I}_{T(RMS)} = 0.8 \text{ A};$ $dV_{com}/dt = 10 \text{ V}/\mu \text{s};$ gate open circuit		0.5	-	-	A/ms
		$V_D = 400 \text{ V}; \text{ T}_j = 125 \text{ °C}; \text{ I}_{T(RMS)} = 0.8 \text{ A};$ $dV_{com}/dt = 1 \text{ V}/\mu s; \text{ gate open circuit}$		1	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T2	main terminal 2		N
2	G	gate		
3	T1	main terminal 1	() {) {) 3 2 1 TO-92 (SOT54)	G sym051

6. Ordering information

Table 3. Ordering information

Type number	Package	Orderable part number	Packing	Small packing	Package	Package
	Name		method	quantity	version	issue date
BTA301-1000D	TO92	BTA301-1000D,412	Bulk	1000	TO92L	10-May-2021

7. Marking

Table 4.	Marking	codes
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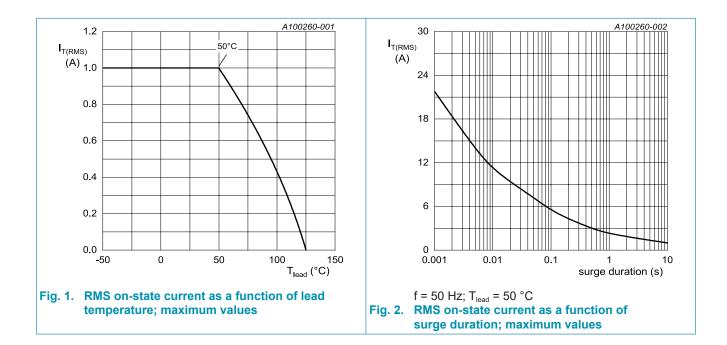
Type number	Marking codes
BTA301-1000D	01-10D

8. Limiting values

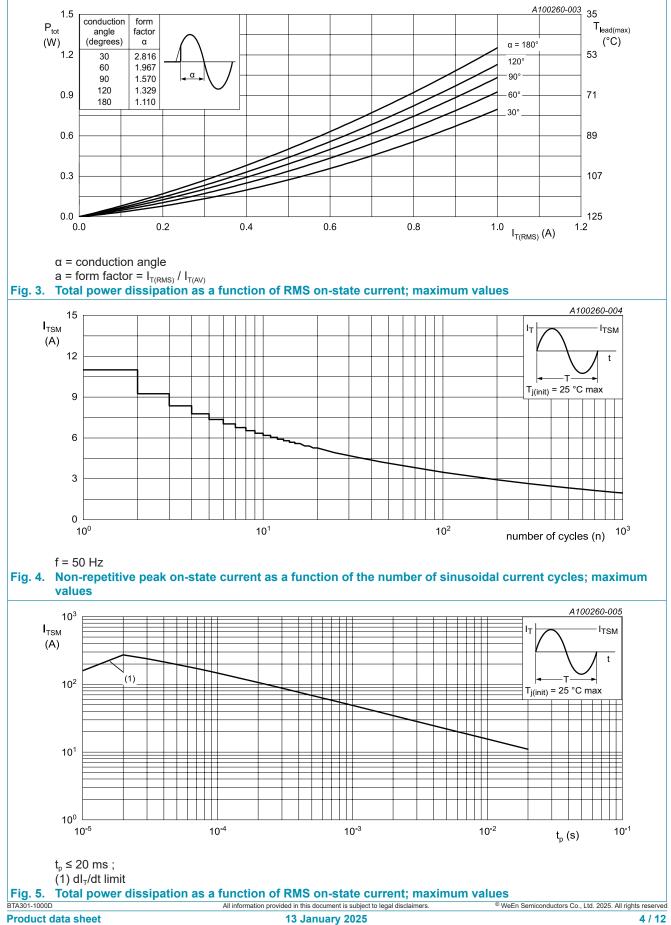
Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V_{DRM}	repetitive peak off-state voltage			1000	V
V_{DRM}	repetitive peak reverse voltage			1000	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _{lead} ≤ 50°C; <u>Fig. 1; Fig. 2; Fig. 3</u>		1	A
I _{TSM}	non-repetitive peak on- state current	full sine wave; t _p = 20 ms; T _{j(init)} = 25 °C; <u>Fig. 4; Fig. 5</u>		11	A
		full sine wave; t_p = 16.7 ms; $T_{j(init)}$ = 25 °C		12.1	А
l ² t	l ² t for fusing	t _p = 10ms; sine wave		0.61	A ² /s
dl _⊤ /dt	rate of rise of on-state current	I _G = 20mA		100	A/µs
I _{GM}	peak gate current			1	А
P_{GM}	peak gate power			2	W
$P_{G(AV)}$	average gate power	over any 20 ms period		0.1	W
T _{stg}	storage temperature			-40 to 150	°C
T _j	operating junction temperature			-40 to 125	°C



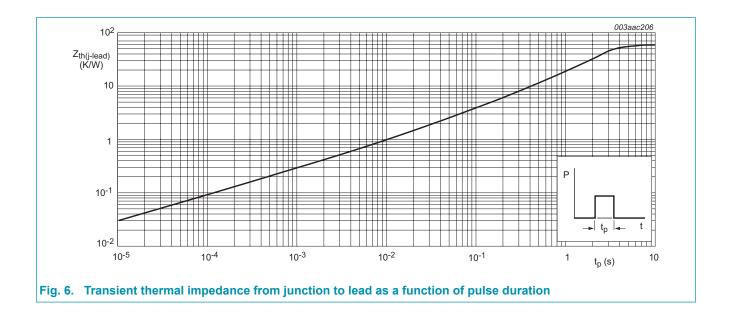
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9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
$R_{th(j-lead)}$	thermal resistance from junction to lead	<u>Fig. 6</u>		-	-	60	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	in free air		-	150	-	K/W



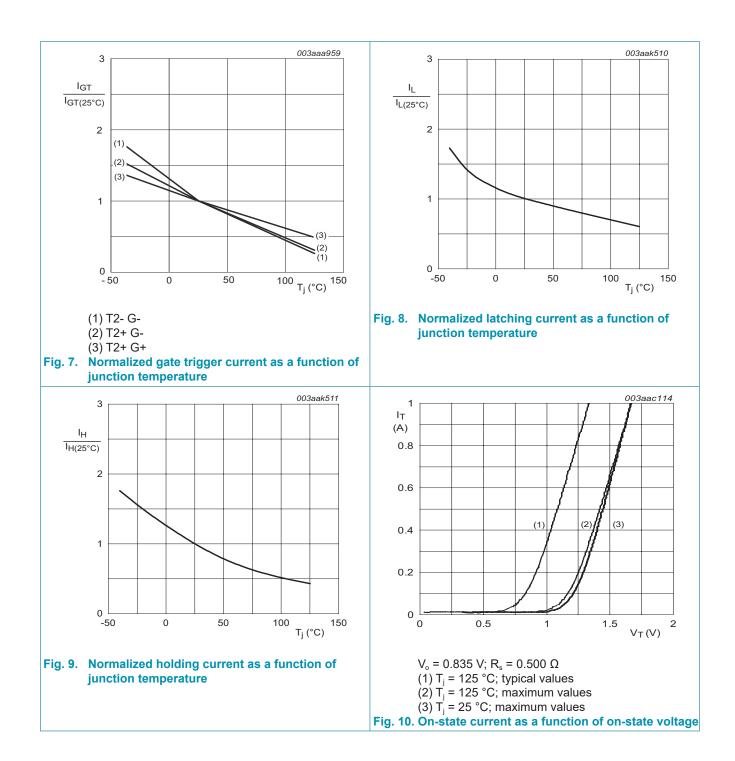
10. Characteristics

Table 7. Characteristics

Parameter	Conditions	Notes	Min	Тур	Max	Unit
aracteristics	·					
gate trigger current	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G+};$ T _j = 25 °C; <u>Fig. 7</u>		0.25	-	5	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G-};$ $T_{j} = 25 \text{ °C}; \text{ Fig. 7}$		0.25	-	5	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2- G-};$ T _j = 25 °C; Fig. 7		0.25	-	5	mA
latching current	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G+};$ $T_{j} = 25 \text{ °C}; \text{ Fig. 8}$		-	-	10	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G-};$ $T_{j} = 25 \text{ °C}; \text{ Fig. 8}$		-	-	20	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2- G-};$ $T_{j} = 25 ^{\circ}\text{C}; \text{ Fig. 8}$		-	-	10	mA
holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	10	mA
on-state voltage	I _T = 0.85 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.30	1.60	V
gate trigger voltage	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T}_{j} = 25 \text{ °C};$ Fig. 11		-	0.85	1.00	V
	V _D = 400 V; I _T = 0.1 A; T _j = 125 °C; Fig. 11		0.2	0.3	-	V
off-state current	V _D = 1000 V; T _j = 125 °C		-	0.1	0.5	mA
reverse current	V _R = 1000 V; T _j = 125 °C		-	0.1	0.5	mA
characteristics						
rate of rise of off-state voltage	$V_{DM} = 670 \text{ V}; \text{ T}_{j} = 125 \text{ °C}; (V_{DM} = 67\% \text{ of } V_{DRM});$ exponential waveform; gate open circuit		-	150	-	V/µs
rate of change of commutating current	$ V_D = 400 \text{ V}; \text{T}_{\text{j}} = 125 ^{\circ}\text{C}; \text{I}_{\text{T(RMS)}} = 0.8 \text{ A}; \\ dV_{\text{com}}/\text{dt} = 10 \text{ V}/\mu\text{s}; \text{ gate open circuit} $		0.5	-	-	A/ms
	$V_D = 400 \text{ V}; \text{ T}_j = 125 \text{ °C}; \text{ I}_{T(RMS)} = 0.8 \text{ A};$ $dV_{com}/dt = 1 \text{ V}/\mu\text{s}; \text{ gate open circuit}$		1	-	-	A/ms
	aracteristics gate trigger current gate trigger current latching current holding current on-state voltage gate trigger voltage off-state current reverse current characteristics rate of rise of off-state voltage rate of change of	aracteristics gate trigger current $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2+ G+}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 7 \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2+ G-}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 7 \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 7 \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2+ G+}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 8 \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2+ G+}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 8 \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2+ G-}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 8 \\ V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 8 \\ \hline \text{Nolding current} \qquad V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-}; \\ T_j = 25 ^{\circ}\text{C}; Fig. 8 \\ \hline \text{Nolding current} \qquad V_D = 12 \text{ V}; T_j = 25 ^{\circ}\text{C}; Fig. 9 \\ \text{on-state voltage} \qquad I_T = 0.85 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 10 \\ \hline \text{gate trigger voltage} \qquad V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; \\ Fig. 11 \\ \hline V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C}; \\ Fig. 11 \\ \hline \text{v_D} = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C}; \\ \hline \text{Fig. 11} \\ \hline \text{v_D} = 1000 \text{ V}; T_j = 125 ^{\circ}\text{C} \\ \hline \text{characteristics} \\ \hline \text{rate of rise of off-state} \\ \text{voltage} \qquad V_D = 670 \text{ V}; T_j = 125 ^{\circ}\text{C}; (V_{DM} = 67\% \text{ of } V_{DRM}); exponential waveform; \\ gate open circuit \\ \hline \text{v_D} = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; \text{ I}_{T(RMS)} = 0.8 \text{ A}; \\ \hline \text{dV}_{com}/\text{dt} = 10 \text{ V}/\mu; \text{gate open circuit} \\ \hline V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; \text{ I}_{T(RMS)} = 0.8 \text{ A}; \\ \hline \text{dV}_{com}/\text{dt} = 10 \text{ V}/\mu; \text{ gate open circuit} \\ \hline \text{V_D} = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; \text{ I}_{T(RMS)} = 0.8 \text{ A}; \\ \hline \text{dV}_{com}/\text{dt} = 10 \text{ V}/\mu; \text{ gate open circuit} \\ \hline \text{dV}_{D} = 400 \text{ V}; \text{ T}_j = 125 ^{\circ}\text{C}; \text{ I}_{T(RMS)} = 0.8 \text{ A}; \\ \hline \text{dV}_{com}/\text{dt} = 10 \text{ V}/\mu; \text{ gate open circuit} \\ \hline \text{dV}_{D} = 400 \text{ V}; \text{ T}_j = 125 ^{\circ}\text{C}; \text{ I}_{T(RMS)} = 0.8 \text{ A}; \\ \hline \text{dV}_{com}/\text{dt} = 10 \text{ V}/\mu; \text{ gate open circuit} \\ \hline \text{dV}_{D} = 400 \text{ V}; \text{ T}_j = 125 ^{\circ}\text{C};$	aracteristics gate trigger current $V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}; \text{ T2+ G+}; \\ T_{J} = 25 ^{\circ}\text{ C}; Fig. T \\ V_{D} = 12 \text{ V}; 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T_{J} = 25 ^{\circ}\text{ C}; Fig. 10 \\ \hline qate trigger voltage \qquad V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}; \text{ T3- 25 }^{\circ}\text{ C}; \\ Fig. 11 \\ \hline V_{D} = 400 \text{ V}; I_{T} = 0.1 \text{ A}; \text{ T3- 125 }^{\circ}\text{ C}; \\ \hline reverse current \qquad V_{D} = 1000 \text{ V}; \text{ T3- 125 }^{\circ}\text{ C} \\ \hline reverse current \qquad V_{R} = 1000 \text{ V}; \text{ T3- 125 }^{\circ}\text{ C}; \\ \hline voltage \qquad V_{D} = 670 \text{ V}; \text{ T3- 125 }^{\circ}\text{ C}; (V_{DM} = 67\% \text{ of } V_{DRM}); exponential waveform; \\ gate open circuit \\ \hline rate of rise of off-state \\ voltage \qquad V_{D} = 400 \text{ V}; \text{ T3- 125 }^{\circ}\text{ C}; \text{ I}_{(RMS)} = 0.8 \text{ A}; \\ dV_{com}/dt = 10 \text{ V}/\mu_{S}; gate open circuit \\ \hline V_{D} = 400 \text{ V}; \text{ T3- 125 }^{\circ}\text{ C}; \text{ I}_{(RMS)} = 0.8 \text{ A}; \\ dV_{com}/dt = 10 \text{ V}/\mu_{S}; gate open circuit \\ \hline V_{D} = 400 \text{ V}; 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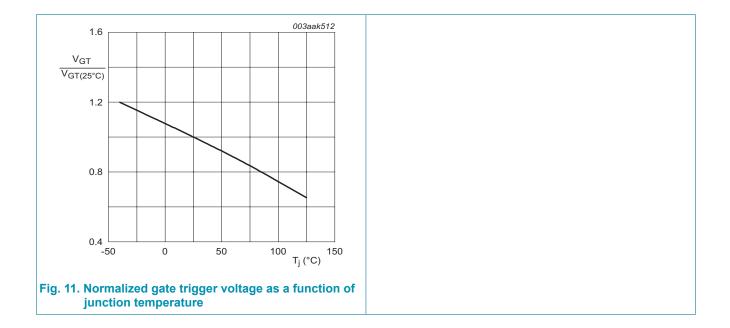
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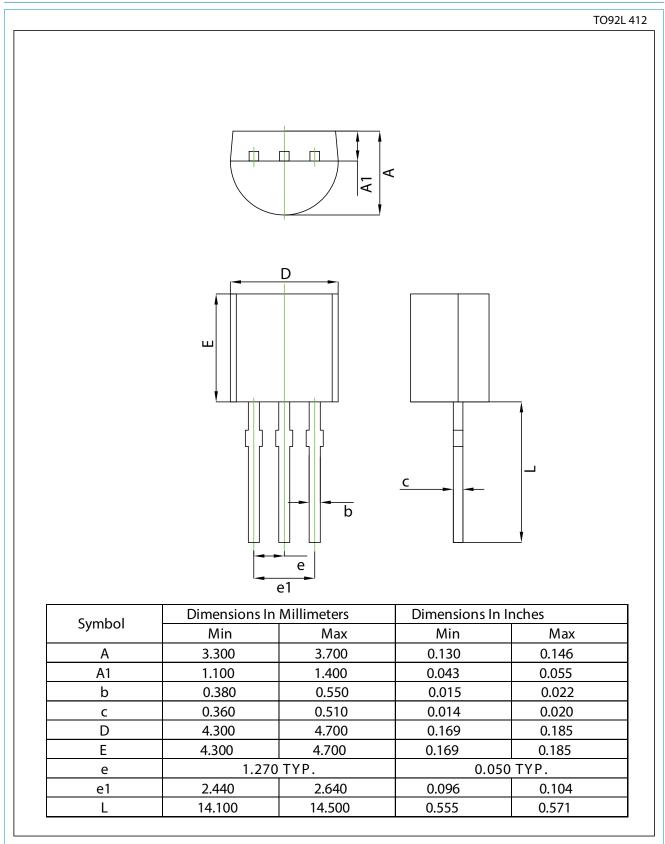


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11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

- [2] The term 'short data sheet' is explained in section "Definitions".
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